TOSHIBA Diode Silicon Epitaxial Planar Type

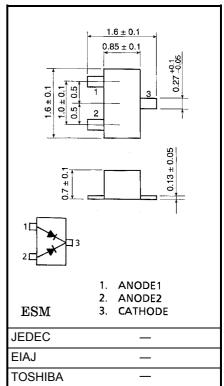
1SS361F

Ultra High Speed Switching Applications

- Small package : 1608 Flat lead
- Excellent in forward current and forward voltage characteristics $: V_F(3) = 0.9V (typ.)$
- Fast reverse recovery time: $t_{rr} = 1.6ns$ (typ.)
- Small total capacitance $: C_{T} = 0.9 pF (typ.)$

Maximum Ratings ($Ta = 25^{\circ}C$)

Characteristic	Symbol	Rating	Unit				
Maximum (peak) reverse voltage	V _{RM}	85	V				
Reverse voltage	V _R	80	V				
Maximum (peak) forward current	I _{FM}	300 (*)	mA				
Average forward current	Ι _Ο	100 (*)	mA				
Surge current (10ms)	I _{FSM}	2 (*)	А				
Power dissipation	Р	100	mW				
Junction temperature	Tj	125	°C				
Storage temperature range	T _{stg}	T _{stg} -55~125					
(*) Unit rating. Total rating = unit rating × 1.5							



Weight: 2.3 mg

Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V _{F (1)}	-	I _F = 1mA	_	0.60	_	
	V _{F (2)}	_	I _F = 10mA	_	0.72	_	V
	V _{F (3)}	-	I _F = 100mA	_	0.90	1.20	
Reverse current	I _{R (1)}	_	V _R = 30V	_	_	0.1	
	I _{R (2)}	_	V _R = 80V	_	_	0.5	μ A
Total capacitance	CT	_	V _R = 0, f = 1MH _z	_	0.9	3.0	pF
Reverse recovery time	t _{rr}		I _F = 10mA (Fig.1)	_	1.6	4.0	ns

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damage to property.
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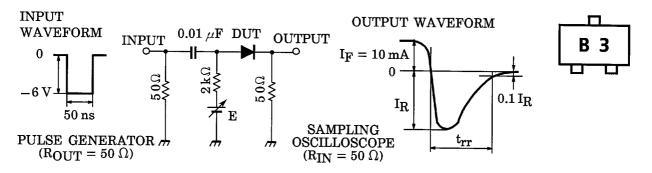
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Unit in mm

000707EAA1

Fig.1 Reverse Recovery Time (trr) Test Circuit

Marking



TOSHIBA

